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Application/Control No.	Applicant(s)/Patent under Reexamination
09/965,267	BATKE ET AL.
Examiner	Art Unit
Dustin Nguyen	2154

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	SEARCHED				
Class	Subclass	Date	Examiner		
370	252, 256	11/6/2006	DN		
709	245	11/6/2006	DN		
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Subclass	Data	
	Date	Examiner
222, 245	11/6/2006	DN
252, 256	11/6/2006	DN

SEARCH NO (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
updated EAST, search non-patent literature (google, IEEE and ACM)	11/6/2006	DN
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